

**Search Notes****Application/Control No.**

10/780,362

**Examiner**

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**Applicant(s)/Patent under Reexamination**

RABENKO ET AL.

**Art Unit**

2664

**SEARCHED**

Class	Subclass	Date	Examiner
370	508	12/2/2005	BQN
370	350	12/2/2005	BQN
370	512	12/2/2005	BQN
370	521	12/2/2005	BQN
370	401	12/2/2005	BQN
375	350	12/2/2005	BQN
375	229	12/2/2005	BQN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	12/2/2005	BQN
Consulted with Andrew Lee	12/2/2005	BQN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner